Suzaku XIS Contamination Status

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http://space.mit.edu/XIS/monitor/contam

Outline

- contamination history independent of model
- method for determining composition, time dependence, spatial dependence
- interpretation from 2006 XIS "Bakeout Review" possible source









normalized counts s⁻¹ keV⁻¹normalized counts s⁻¹ keV⁻¹

1 E0102-72.3 - XIS1, 20050831, Gaussian fits



Key Objects

	Stable (Incident Spectrum known)	Extended over FOV	Always Observable ?	Energy Range	Target of the contaminant study
RXJ1856	Yes (maybe)	No	No	0.2-1keV	Composition
E0102	Yes	No	Yes	0.4-3keV	Evolution
Cygnus Loop	Yes at somelevel	Yes	No	0.2-3keV	Uniformity
PK2155	No but Smooth	No	No	0.2-12keV	Composition
Atmospheric F.L.	No	Yes	Yes	0.39keV 0.52keV	Uniformity Evolution

Step I – Composition

- fit central contamination
 - RXJ1856, PKS2155 fit H,C,N,O absorption
 - H is proxy for changes below
 C edge (maybe He?)
 N only allowed for BI
 - E0102 freeze H,N to previous fit trends
- absorption model
 - hcnofcol XSPEC model parameters are column densities of H,C,N,O,F uses Verner et al. (1996) cross-sections no XAFS, just XSPEC



Carbon













C: O Ratio

C: N Ratio



Step 2 – Spatial Dependence

- assume central composition and time dependence
- bright Earth data
 - measure NI K / OI K vs. R (assume flat field)
- confirm with Cygnus Loop, clusters



Spatial Dependence



Spatial Dependence



How Well Do We Do?

1 E0102-72.3 - XIS3, 20060627, w/ HCNO IACHEC (edm)



Model Quality – On Axis



Model Quality – Off Axis



Interpretation

from March 2006 XIS Bakeout Review

Non-uniformity of the contamination



Non-uniformity of the contamination



OBF structure and temp profile



Results of baking

- Total CVCM of the satellite was ~31g before the baking.
- Total outgas removed during the baking was estimated roughly as ~70g.
- Major fraction of the condensable material was removed by baking.
- Upper limit to the OBF contamination was estimated as ~0.5µg/cm².

Observed XIS contamination is 2 orders of magnitude larger than the estimation based on the satellite baking.

CVCM = Collected Volatile Condensable Mass

Possible difference from the satellite baking

1. Some components did not join the satellite baking.

XRT, XRS-CDP/CAP/ACHE, Dewar, XRS-FW, XIS-S/AE, HXD-S/AE, HXD-PSU, SAP, BAT, SBR, AOCU, STT-AE/DE, NSAS, WHNS(extra)

- Operation temperature of some component is higher than the baking temperature.
 IRU: operation temp of 60°C
- 2. Unexpected failure?

IRU: inertia reference unit

- Two units are mounted
 SA (4 axis) and SB (1 aixs)
- Operation temperature: 60°C
- Tar-like material was found on the housing after the TV test of Astro-F
 - IR analysis: phthalic ester (DEHP etc)
 - Most likely produced from the shock absorber in the IRU.
 - Component test show large mass loss (40g --> 37.3g in 2 months in vacuum)

Leak of tar-like material at IRU-SA

- A leak of tar-like material was found to leak at the mount point of IRU-SA on Oct. 26, 2005, after the thermal vacuum test of Astro-F (akari).
 - DEHP (a common form of phthalic ester)



C24H38O4

 $E = 1.3 \times 10^4 \,\mathrm{K}$ $P_0 = 7.1 \times 10^{14} \,\mathrm{Pa}$

One of the most common outgas in the satellite.

DEHP = diethylhexyl phthalate

Summary of interpretation

- 1. If the contaminant fills inside the satellite uniformly...
 - Total amount of outgas escaped from the satellite would be very large, 6–33 g.
 - 2. The vapor pressure becomes probably higher than the saturated vapor pressure of DEHP at satellite temperature.
 - 3. It cannot explain the difference of contamination among XIS-0,1,2,3.
- 2. Outgas may reach OBF almost directly from the source.

Summary

- contamination level increased quickly (XIS after 3 months ~ ACIS after 6 years) now decreasing at 10% per year
- C:N:O changes with time started out C:O ~ 6 ~ DEHP, but not now
- decrease below C-edge: H? He? something else?
- A_{eff} (E > 0.7 keV) is good to ~5%
 A_{eff} (E < 0.7 keV) is (not) good to 10-50%, especially near edges

Contamination WG Plan (1/2)

• standardize how we tabulate contamination

- C,N,O,F, etc. in column density units (10¹⁸ cm⁻²)
 - useful for composition modeling
- optical depth τ at some energy
 - C, O edges are useful for comparison
 - OVIII and other bright lines are practical
 - ~ contamination model independent
 - au converts directly into Aeff, useful for observers

Contamination WG Plan (2/2)

Steve?

Andy B.

Eric

- A/I for all instruments
 - estimates of C,N,O,F, etc. columns (multiple epochs are fine)
 - estimates of τ @ C edge, O edge, I keV
- ACIS: Herman
- XMM EPIC MOS: Steve
- XMM EPIC pn: Steve?
- XMM EPIC RGS:
- Suzaku XIS:
- Swift XRT:





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normalized counts s⁻¹ keV⁻¹normalized counts s⁻¹ keV⁻¹

1 E0102-72.3 - XIS3, 20050813, Gaussian fits

DEHP pressure

Two estimations







Sequence

- Launch : valve (close)
- Just after the launce: open. Close, before 1st ΔV .
- BDY-T & CCD-T : +25C \rightarrow -40C in one day
- After the end of sequence of ΔV , valve open.
- XIS-ON & Parameter Setting
- CCD daq. starts. (CCD-T @ -40C), observe door cal. source.
- CCD-T : $-40C \rightarrow -90C$
- Parameter Tuning
- Door open
- Start observing X-ray objects.



Caveats for Suzaku from 2007

> above 0.6 keV

- Contamination well-modeled for XIS1,2,3, ~10% sys. error
- contamination on XIS0 is underestimated for mid-2006 onward, fixed in June 2007 CALDB release

between 0.3-0.6 keV

- > C/O ratio is not well constrained (C/O > 6?)
- changes A_{eff} from the C edge (0.28 keV) to just above the O edge (0.53 keV)
- > could introduce spurious features near the O edge

below 0.3 keV (the "C-band")

- decrease in A_{eff} with time is seen in some soft sources, e.g. RXJ1856 (shown)
- > C+O insufficient, additional elements required
- > composition may be time dependent
- C-band calibration is uncertain at this stage

extended sources

- > spatial distribution is modeled from BI chip only
- FI chips might have different distributions

